

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	((first adj Pass/Fail adj signal adj indicative adj2 success adj failure adj3 operation adj outputted) and (each adj cell adj array adj group)). clm.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/28 12:46
L2	1	makamura-hiroshi.inv.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/28 12:46
L3	0	yamamura-toshio.inv.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/28 12:47
L4	124	yamamura-toshio.inv.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/28 12:47
S1	30086	(memory adj cell adj array)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:20
S2	8701	S1 and group	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:20
S3	7340	pass/fail or (pass adj fail) or pass-fail	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:38
S4	7089	S3 and (test\$3 or detect\$3 or monitor\$3 or measur\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:21
S5	3370	S4 and (program or erase)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:22
S6	432	S5 and EEPROM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:22

S7	128	S6 and NAND	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:22
S8	128	S7 and second	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:23
S9	123	S8 and plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:23
S10	95	S9 and parallel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:25
S11	47	S10 and matrix	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:32
S12	7	S11 and (second adj3 signal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:32
S13	3	S11 and ((pass/fail) adj2 signal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/01 16:41
S14	7366	pass/fail or (pass adj fail) or pass-fail	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S15	7115	S14 and (test\$3 or detect\$3 or monitor\$3 or measur\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S16	3382	S15 and (program or erase)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45

S17	436	S16 and EEPROM	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S18	129	S17 and NAND	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S19	129	S18 and second	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S20	123	S19 and plurality	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S21	95	S20 and parallel	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S22	47	S21 and matrix	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S23	3	S22 and ((pass/fail) adj2 signal)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S24	7366	pass/fail or (pass adj fail) or pass-fail	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:45
S25	3382	S15 and (program or erase)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:47
S26	6782	365/200	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:47















S27	182	S15 AND S26	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:48
S28	112	S27 and S16	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:47
S29	21	S28 and S17	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:47
S30	2299	365/185.33	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:48
S31	15	S20 AND S26	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:48
S32	1141	365/185.21	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:48
S33	14	S32 and S15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:49
S34	1	makamura-hiroshi.inv.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:49
S35	121	yamamura-toshio.inv.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/11 16:50

10/694861  
 Inventor: MAKAMURA, HIROSHI, et al  
 Status: 71 - RESPONSE TO NON-FINAL OFFICE ACTION ENTERED AND FORWARDED TO EXAMINER  
 Title: SEMICONDUCTOR MEMORY

Examiner: NGUYEN, NAM

GAU: 2824  
 Classification: 365/201.000

All tab report (29 items, not sorted)















Img	Status	DocCode	Document Type	Date	Pages	Annotations
	13	WFEE	Fee Worksheet (PTO-875)	10/28/2005	1	
	13	FWCLM	Index of Claims	10/28/2005	1	
	7	A..	Amendment - After Non-Final Rejection	10/25/2005	2	
	7	CLM	Claims	10/25/2005	3	
	7	REM	Applicant Arguments or Remarks Made in an Amendment	10/25/2005	3	
	7	CTNF	Non-Final Rejection	07/25/2005	6	
	7	1449	List of References cited by applicant and considered by examiner	07/25/2005	1	
	7	892	List of references cited by examiner	07/25/2005	1	
	7	FWCLM	Index of Claims	07/25/2005	1	
	7	SRFW	Search information including classification, databases and other search related notes	07/25/2005	1	
	7	BIB	Bibliographic Data Sheet	07/25/2005	1	
	7	SRNT	Examiner's search strategy and results	07/11/2005	4	
	7	PEFR	Applicant Response to Pre-Exam Formalities Notice	03/29/2004	2	
	7	OATH	Oath or Declaration filed	03/29/2004	3	

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Img	Status	Doc Code	Document Type	Date	Pages	Annotations
	7	ADS	Application Data Sheet	03/29/2004	3	
	7	PEFN	Pre-Exam Formalities Notice	01/28/2004	1	
	7	TRNA	Transmittal letter	10/29/2003	2	
	7	SPEC	Specification	10/29/2003	46	
	7	CLM	Claims	10/29/2003	3	
	7	ABST	Abstract	10/29/2003	1	
	7	DRW	Drawings	10/29/2003	12	
	7	FRPR	Foreign Priority Papers Filed	10/29/2003	56	
	7	WFEE	Fee Worksheet (PTO-875)	10/29/2003	1	
	7	WFEE	Fee Worksheet (PTO-875)	10/29/2003	1	
	7	ADS	Application Data Sheet	10/29/2003	2	
	7	IDS	Information Disclosure Statement (IDS) Filed	10/29/2003	3	CONSIDERED 11/28/05
	7	FOR	Foreign Reference	10/29/2003	18	
	7	FOR	Foreign Reference	10/29/2003	16	

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Img	Status	Doc Code	Document Type	Date	Pages	Annotations
	7	136A	Authorization for Extension of Time for all replies	10/29/2003	2	